

Error on field from PIC scheme and its effect on field emission

Kyrre Ness Sjøbæk
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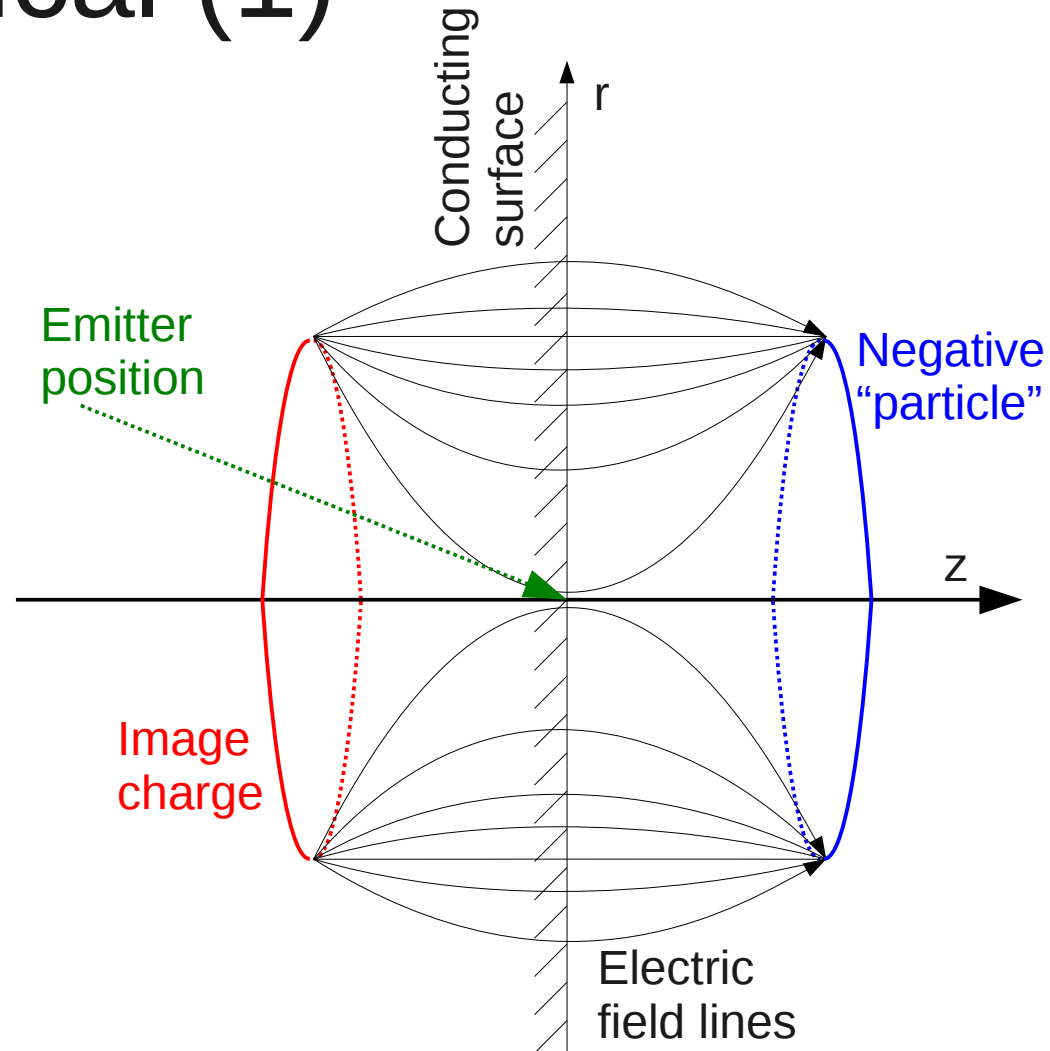
(+ update on time step 26/8)

Outline

- Field from a test particle at (z,r) observed at $(0,0)$
 - Analytical
 - PIC
- PIC field versus analytical field
- Effect on field emission in ArcPIC2D

Field from test particle on tip: analytical (1)

- Due to coordinate system, particles appears as infinitely thin circles with radius r at height z above surface
- Surface is perfectly conducting, so the boundary condition may be approximated by placing an identical but oppositely charged ring at $-z$
- We are interested in the field from a negative test particle located at (r,z) when observed at the emitter position $(0,0)$



Field from test particle on tip: analytical (2)

- This field may be calculated by summing up the field from infinitively many charges dq distributed along the ring
- The single-particle field observed at position (x,y,z) from a particle located at $(0,0,0)$ is given as:
- When swapping observation and test charge position, the sign of E is reversed
- The field from one particle on the emitter is then given as:

$$\vec{E} = \frac{q}{k_e} \frac{\hat{R}}{R^2} \quad \text{where } k_e = 4\pi\epsilon_0$$

and the unit vector $\hat{R} = \frac{\vec{R}}{R}$ where

$$R = \sqrt{x^2 + y^2 + z^2} = \sqrt{r^2 + z^2} \quad \text{and}$$

$$\begin{aligned} \vec{R} &= r \hat{r}(\theta) + z \hat{z} = r(\cos(\theta) \hat{x} + \sin(\theta) \hat{y}) + z \hat{z} \\ &= x \hat{x} + y \hat{y} + z \hat{z} \end{aligned}$$

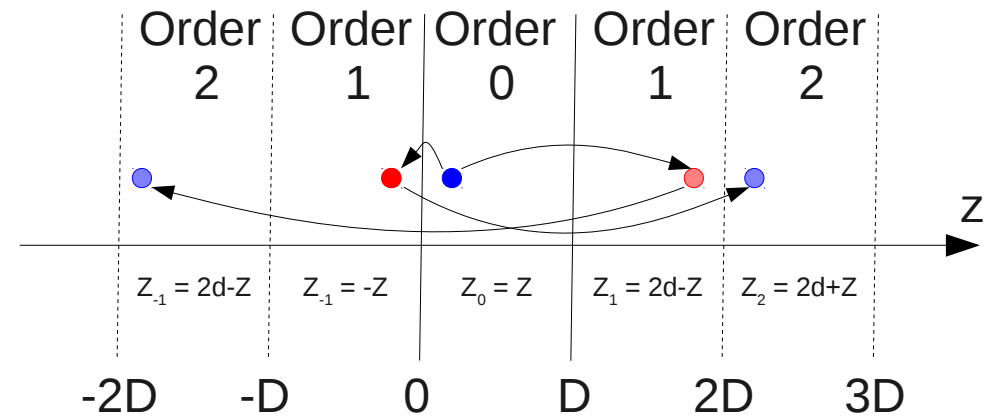
$$\begin{aligned} \vec{E} &= \int \frac{dq}{k_e} \frac{-\hat{R}}{R^2} = \\ &= \frac{\int_0^{2\pi} Q d\theta}{k_e 2\pi} \left(\frac{-z \hat{z}}{R^3} + \frac{\hat{x} \cos \theta + \hat{y} \sin \theta}{R^3} \right) = \\ &= \frac{-Q z \hat{z}}{k_e R^3} = \frac{N_{sp} e z \hat{z}}{k_e R^3} \end{aligned}$$

where $Q = \int dq = -N_{sp} e$ and

e is the electron charge,
 N_{sp} the superparticle ratio

Field from test particle on tip: analytical (3)

- We have two perfectly conducting surfaces, so both requires an image charge



- The image charges are then mirrored on the other surface
- This leads to a series expansion of the field

$$Z_{-i} = -i * D + \begin{cases} D - z & i \text{ odd} \\ z & i \text{ even} \end{cases}$$

$$Z_{+i} = i * D + \begin{cases} D - z & i \text{ odd} \\ z & i \text{ even} \end{cases}$$

$$E_z = E_z(z_0) + \sum_{o=1}^{\infty} (E_z(z_{+i}) + E_z(z_{-i}))$$

Field from test particle on tip: analytical (4)

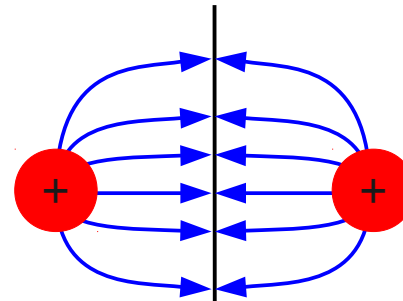
- What is not taken into account in the analytical model is the r-boundary found in the simulation

- In the simulation, this is represented by a Neuman boundary condition at

$$r = R_{\max} = nr :$$

$$\frac{\partial \phi}{\partial r} = 0 \rightarrow E_r = 0$$

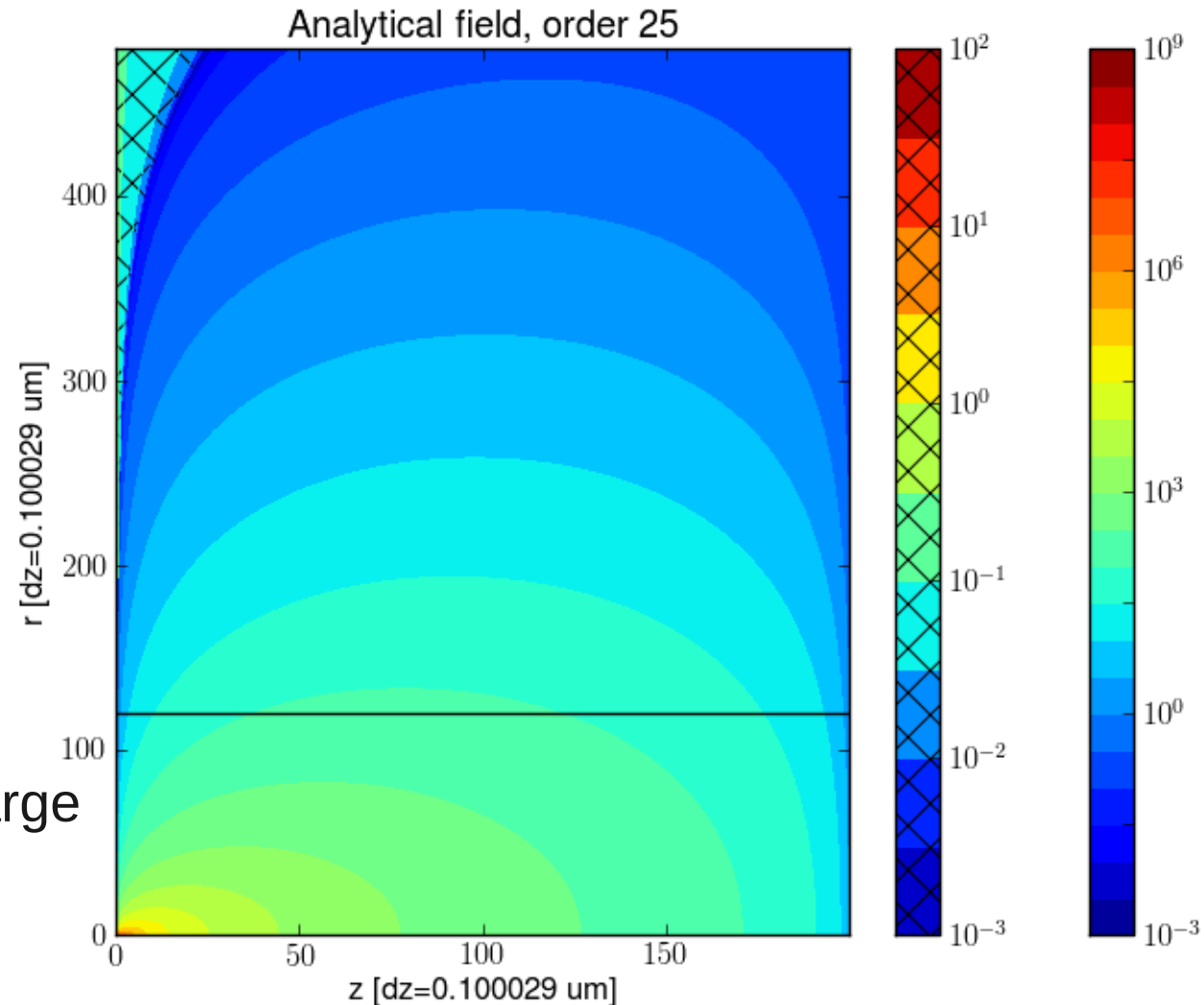
- In an analytical model, this can often be represented by a same-sign image charge



- I was not able to come up with a “mirror” charge distribution for this case
- Thus the analytic and numerical results differ at big r
- I am most interested in field at small r (big r fields anyway small)

Field from test particle on tip: analytical (5)

- The resulting field is shown on the right
 - Black line marks usual system size $12\ \mu\text{m}$
- Parameters:
 - $N_{\text{sp}} = 21.35$
 - Sum order = 25
 - $D = 20\ \mu\text{m}$
- Note negative field at large radius
 - Happens due to image charge field – positive images with $z > D$, negative with $z < 0$
 - Not important at small r



Field from test particle on tip: PIC (1)

- In PIC:
 - 1 The charge is first interpolated onto the grid points
 - 2 Poissons equation solved on the grid points => potential
 - 3 Field calculated by derivative of potential on grid points
 - 4 Field interpolated to observer position
- This leads to underestimation of field and other inaccuracies at short range
- OK for plasma bulk (given that $dz \ll$ typical length scale)
- Problematic at emitter
 - Relevant space-charge shielding charges very close
 - There may be effects of being at $r=0$ which is simultaneously a Neuman boundary and Dirichlet boundary
- Also, field close to $r=r$ is disturbed by Neuman boundary condition

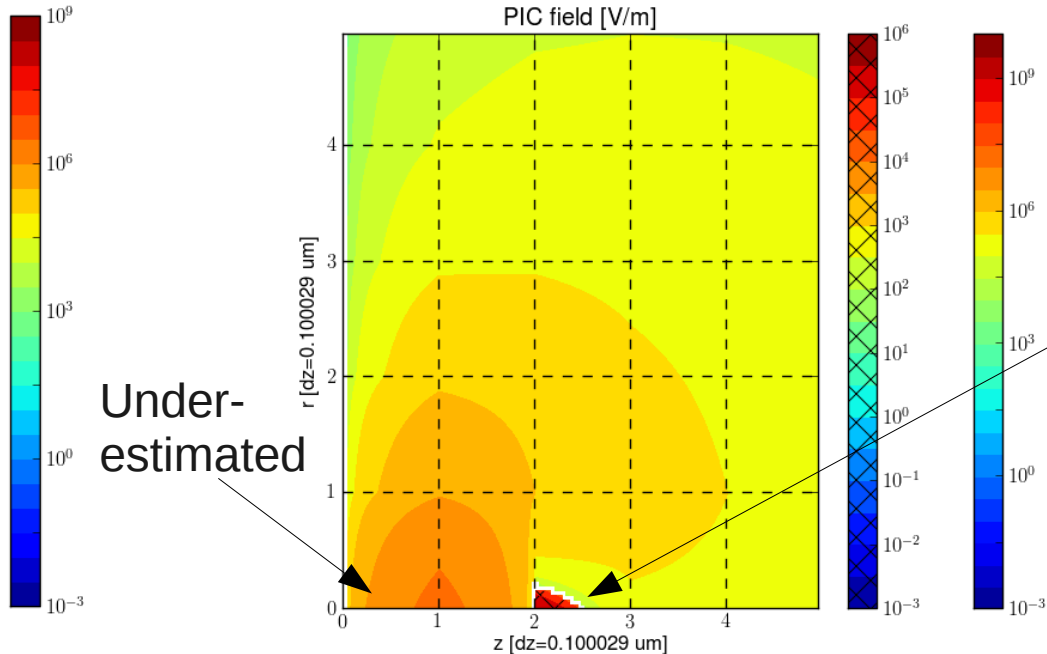
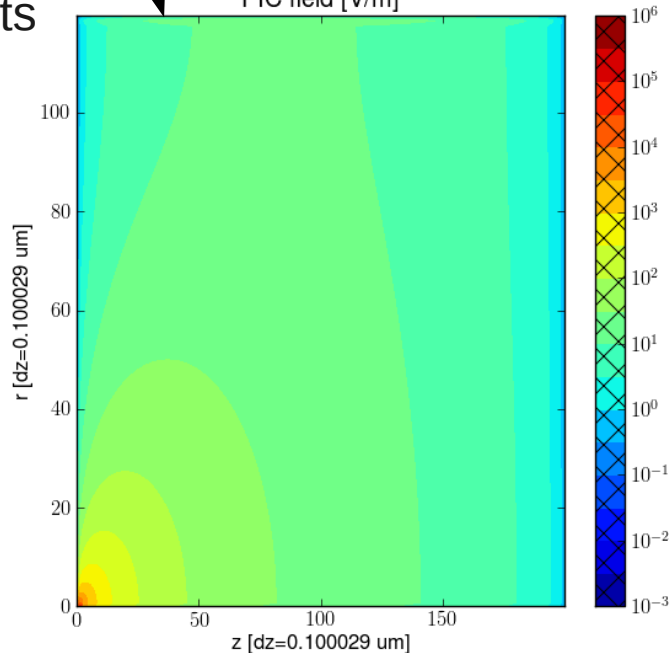
Field from test particle on tip: PIC (2)

Near emitter

(dashed lines = grid)

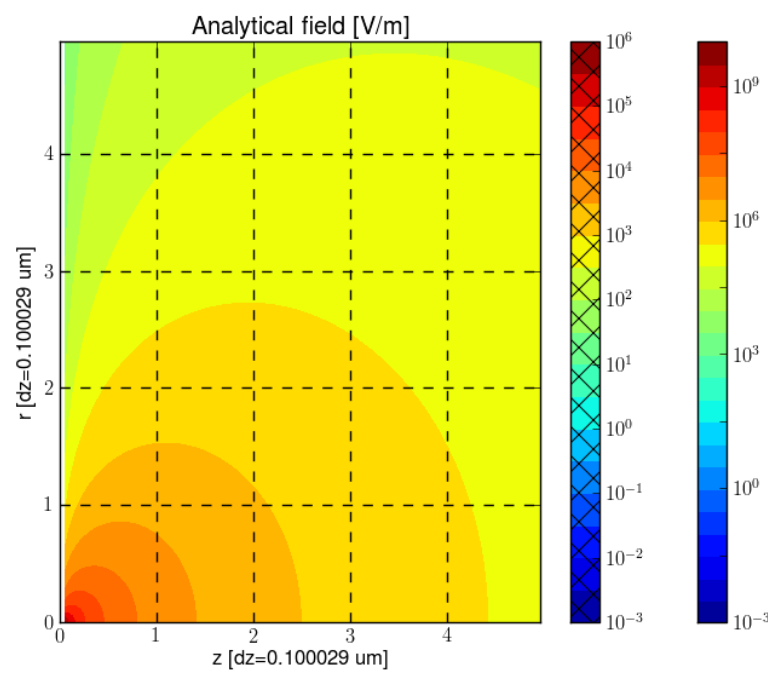
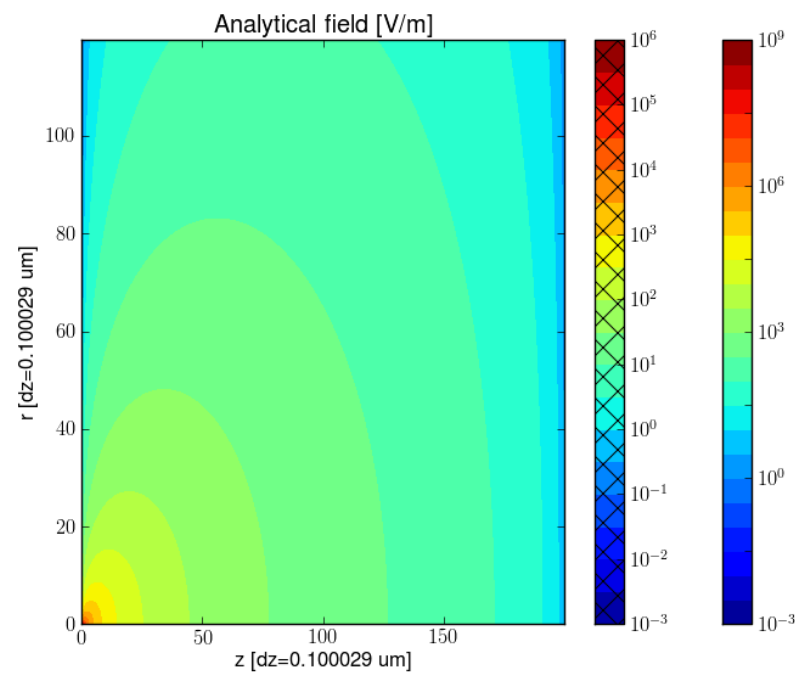
Boundary effects
Whole volume
PIC field [V/m]

PIC

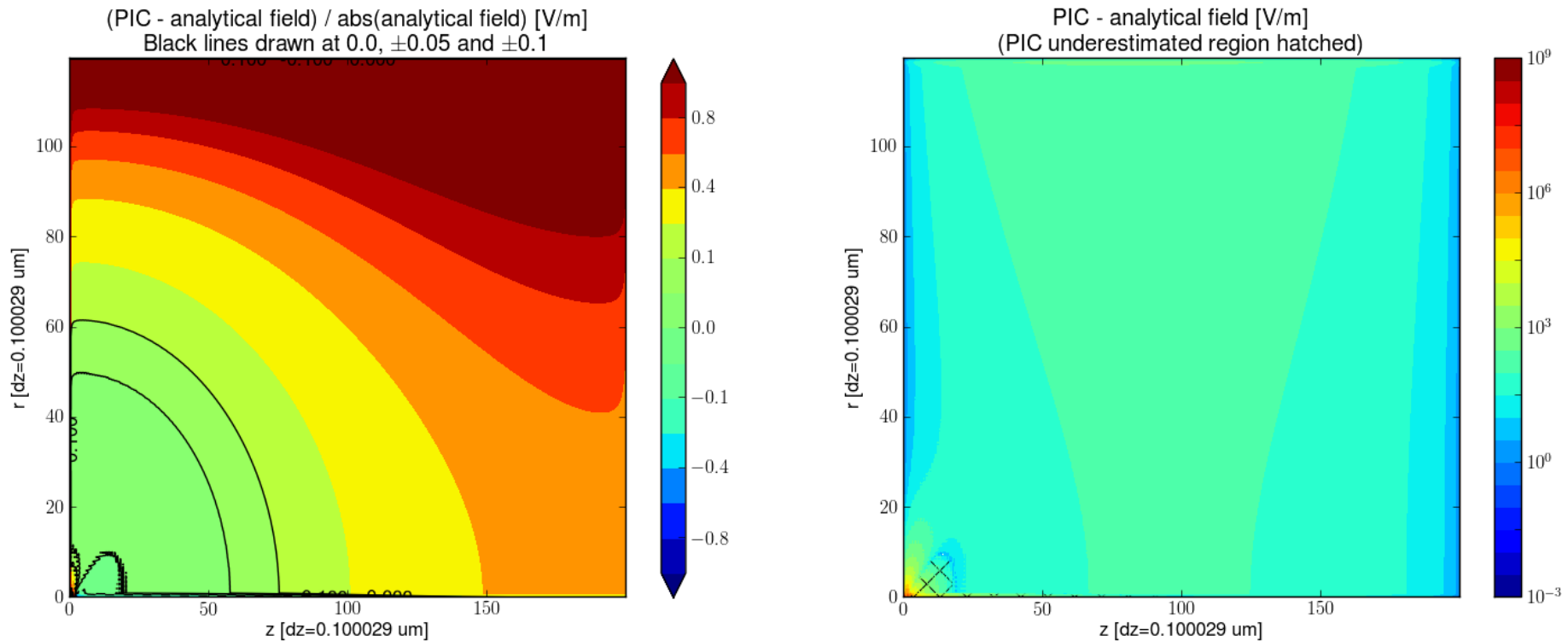


Flipped sign!

Analytical

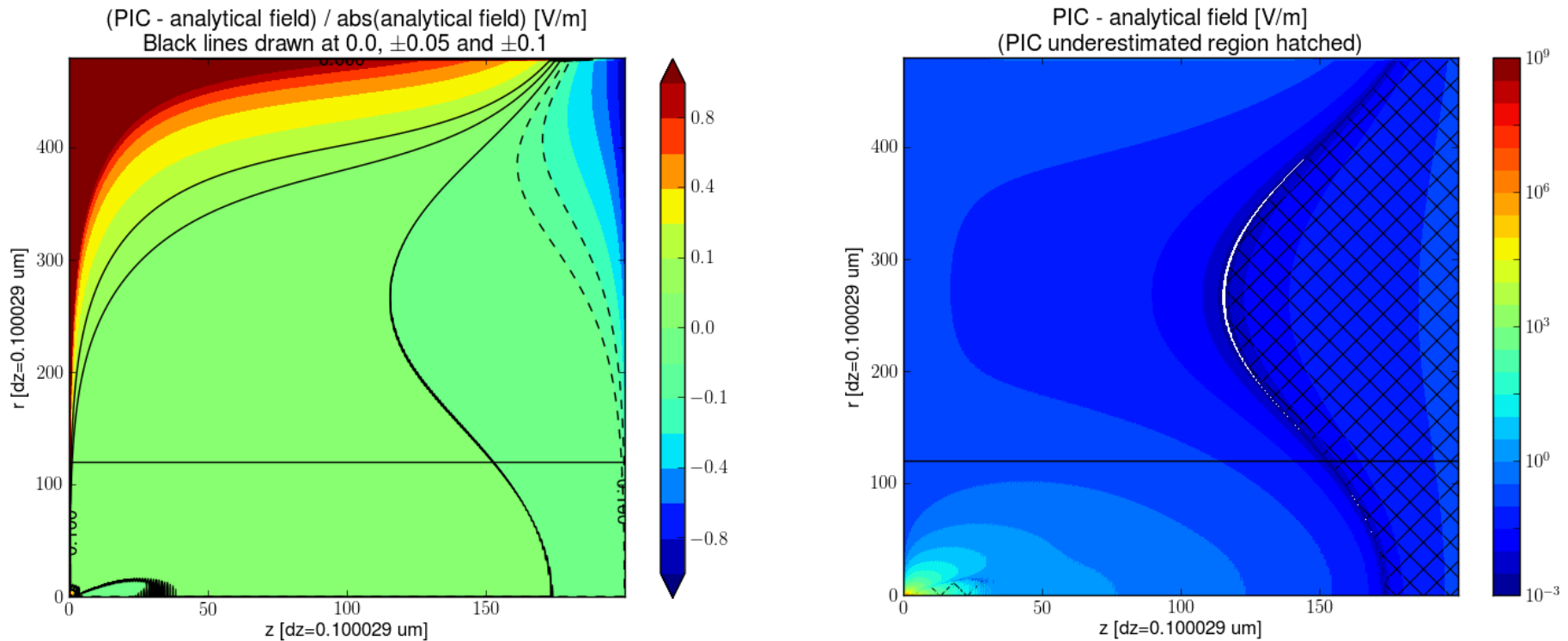


PIC field versus analytical field (1)



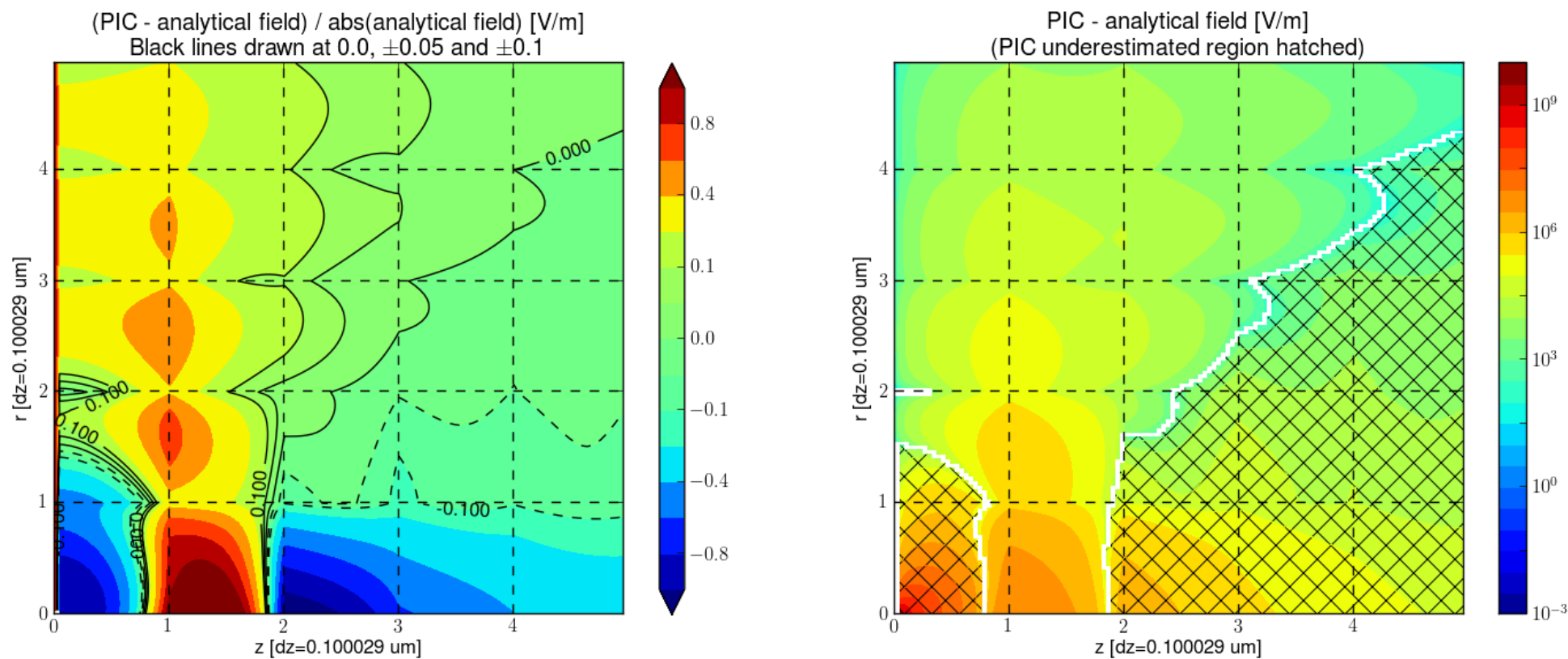
- See that it matches reasonably well far away
 - Boundary effects are visible, and large relative errors
 - These fields are however *absolutely* small (when observed from the emitter)

PIC field versus analytical field (2)



- Mitigation of boundary effect possible by extending the grid (assuming the arc has the same size)
- However this carries the penalty of slowing down the field solver (matrix size $\sim (nr \cdot nz)^2$)

PIC field versus analytical field (3)

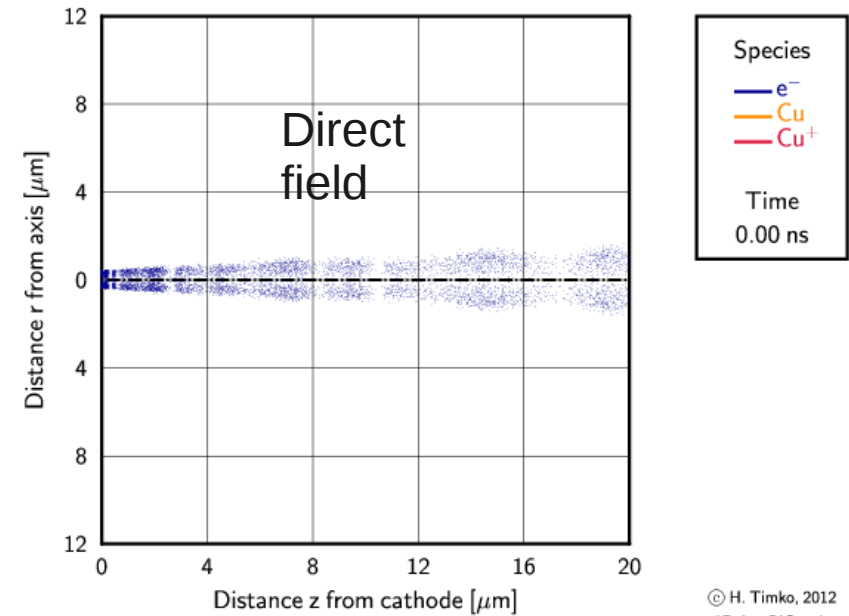


- Field very wrong close to emitter

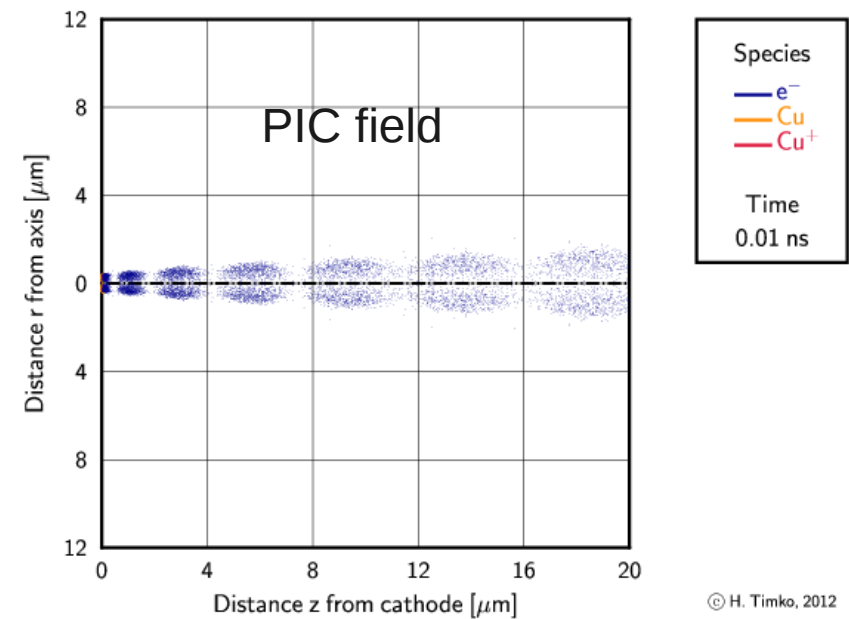
- This is where the recently emitted electrons are found...
- Too-low field => overestimation of emission
 - These extra charges then leads to extra-much space charge -> emission quench
 - This again results in the observed pulsing during space-charge limited Fowler-Nordheim cold field emission

Effect on field emission in ArcPIC2D (1)

- I implemented a test emission model class in ArcPIC using the analytical expression to calculate the tip field
 - Only image charge at -z taken into account
 - No neutrals etc
 - Inter-electron and external field forces handled by PIC
- Still some instability due to field $\sim 1/z^2$
 - Sometimes evaluated with a “close” particle
 - Looks better
 - Less “structured” pulses



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2D Arc-PIC code

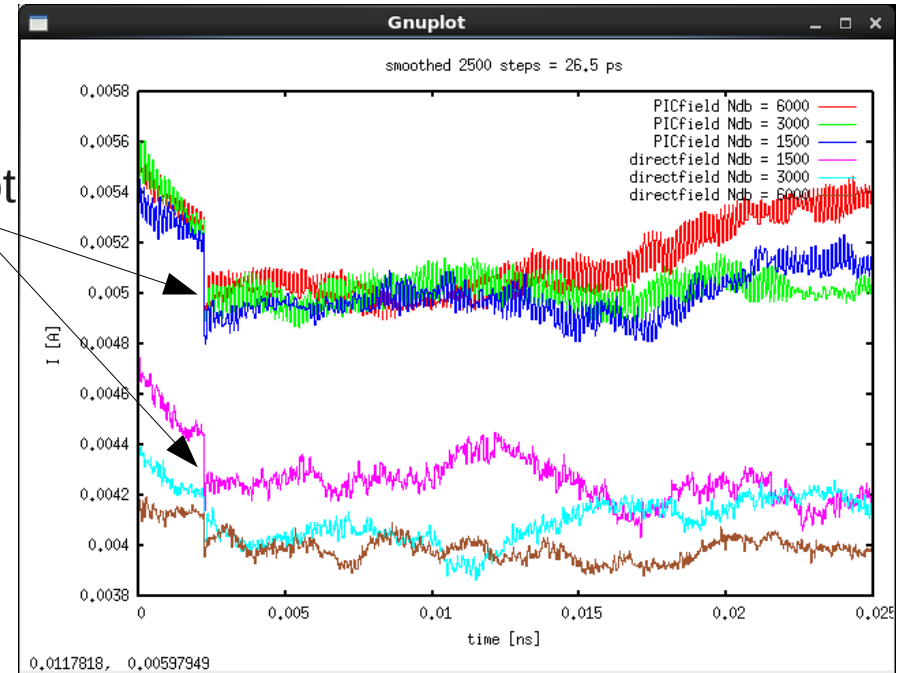


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2D Arc-PIC code

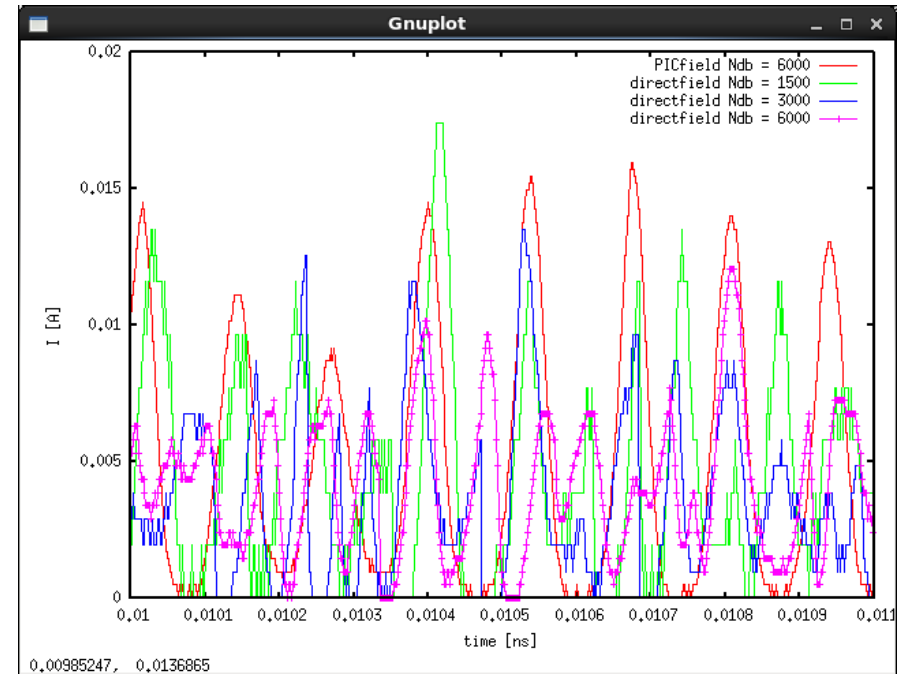
Effect on field emission in ArcPIC2D (2)

- Field emission current reduced significantly
- More random oscillations

Due to first-step overshoot

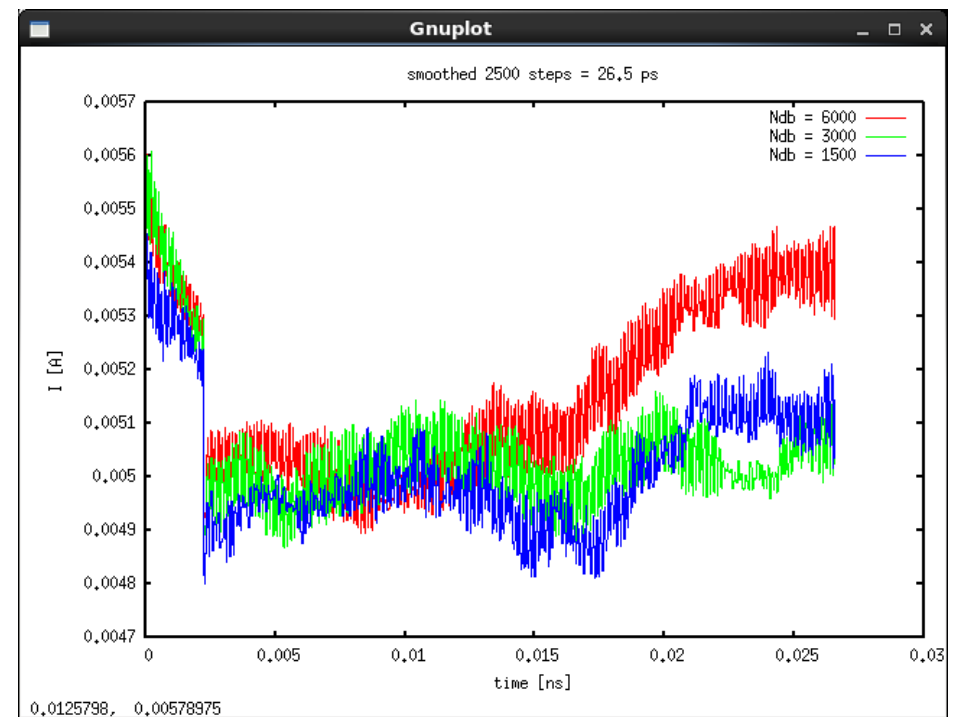
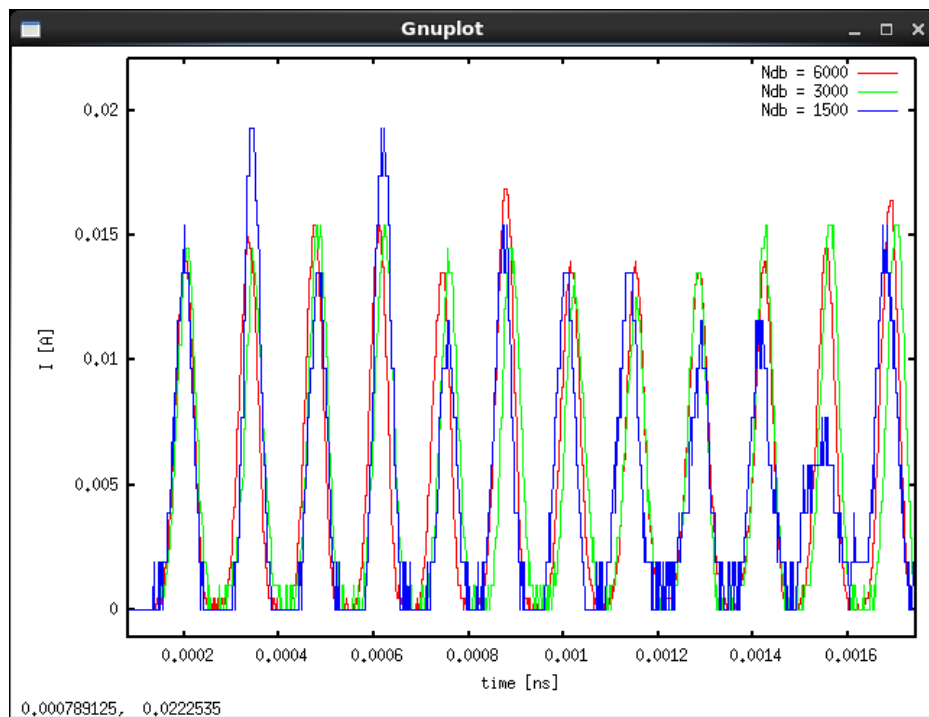


- TODO:
 - Expand test model to include neutrals & ions
 - Run breakdown simulation w/ this model



Appendix

Pulsing is NOT caused by statistics



... but as expected, the higher-Ndb runs are less noisy

Pulsing NOT caused by time step

- See that current well converged in dt
- Increasing dt leads to cycle “emission -> acceleration -> emission”, increasing the average current
- Small dt leads to only 0-1 electrons emitted per time step
- Grid convergence may be more interesting
 - Analytic result is basically an infinite grid, but still noisy (not single frequency tough)

